

## Application Data Sheet

### **Application Information**

**Application Type::** Regular  
**Subject Matter::** Utility  
**Suggested classification::**  
**Suggested Group Art Unit::**  
**CD-ROM or CD-R?::** None  
**Computer Readable Form (CRF)?::** No  
**Title::** A STEREOSCOPIC SYSTEM FOR INSPECTING SEMICONDUCTORS  
**Attorney Docket Number::** 035924-0103  
**Request for Early Publication?::** No  
**Request for Non-Publication?::** No  
**Suggested Drawing Figure::** 1  
**Total Drawing Sheets::** 13  
**Small Entity?::** No  
**Petition included?::** No  
**Secrecy Order in Parent Appl.?::** No

### **Applicant Information**

**Applicant Authority Type::** Inventor  
**Primary Citizenship Country::** Japan  
**Status::** Full Capacity  
**Given Name::** Nobuo  
**Family Name::** KOCHI  
**City of Residence::** Tokyo  
**Country of Residence::** Japan  
**Street of mailing address::** c/o TOPCON CORPORATION  
75-1, Hasunuma-cho, Itabashi-ku  
Tokyo 174-8580, Japan  
**Applicant Authority Type::** Inventor  
**Primary Citizenship Country::** Japan

**Status::** Full Capacity  
**Given Name::** Hirotami  
**Family Name::** KOIKE  
**City of Residence::** Tokyo  
**Country of Residence::** Japan  
**Street of mailing address::** c/o TOPCON CORPORATION  
75-1, Hasunuma-cho, Itabashi-ku  
Tokyo 174-8580, Japan

#### **Correspondence Information**

**Correspondence Customer Number::** 22428

**E-Mail address::** rschwaab@foleylaw.com

#### **Representative Information**

<b>Representative Customer Number::</b>	22428	
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#### **Domestic Priority Information**

<b>Application::</b>	<b>Continuity Type::</b>	<b>Parent Application::</b>	<b>Parent Filing Date::</b>

#### **Foreign Priority Information**

<b>Country::</b>	<b>Application number::</b>	<b>Filing Date::</b>	<b>Priority Claimed::</b>
Japan	2001-062686	03/06/2001	Yes
Japan	2001-062687	03/06/2001	Yes
Japan	2001-062688	03/06/2001	Yes

#### **Assignee Information**

**Assignee name::** TOPCON CORPORATION